**Product data sheet** 

## 1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a TO220F "full pack" plastic package intended for use in applications requiring very high inrush current capability, high thermal cycling performance and high junction temperature capability ( $T_{\text{j(max)}} = 150 \,^{\circ}\text{C}$ ).

### 2. Features and benefits

- · High junction operating temperature capability
- · High thermal cycling performance
- High voltage capability
- Isolated package
- · Planar passivated for voltage ruggedness and reliability
- · Very High current surge capability

## 3. Applications

- · Ignition circuits
- Motor control
- · Protection circuits e.g. SMPS inrush current
- Voltage regulation

### 4. Quick reference data

#### Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{RRM}$	repetitive peak reverse voltage		-	-	800	V
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>h</sub> ≤ 86 °C	-	-	10.2	Α
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; T <sub>h</sub> ≤ 86 °C; Fig. 1; Fig. 2; Fig. 3	-	-	16	А
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 10 \text{ ms}$ ; Fig 4; Fig 5	-	-	210	A
		half sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 8.3 \text{ ms}$	-	-	231	Α
T <sub>j</sub>	junction temperature		-	-	150	°C
Static ch	aracteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$	-	4.5	25	mA
Dynamic	characteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_{j}$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	300	-	-	V/µs

# 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	mb	. 51
2	А	anode		A   K G
3	G	gate		sym037
mb	n.c.	mounting base; isolated		
			1 2 3	

# 6. Ordering information

### **Table 3. Ordering information**

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
TYN16X-800RT	TO220F	TYN16X-800RT,127	Tube	50	SOT186A	14-Nov-2013

# 7. Marking

### **Table 4. Marking codes**

Type number	Marking codes	
	Assembly factory: d	Assembly factory: A
TYN16X-800RT	TYN16X 800RT PJdxxxx xx	TYN16X 800RT PJAxxxx xx

# 8. Limiting values

#### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	800	V
$V_{RRM}$	repetitive peak reverse voltage		-	800	V
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>h</sub> ≤ 86 °C	-	10.2	А
$I_{T(RMS)}$	RMS on-state current	half sine wave; T <sub>h</sub> ≤ 86 °C; Fig. 1; Fig. 2; Fig. 3	-	16	А
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 10 ms; Fig 4; Fig 5	-	210	А
		half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 8.3 ms	-	231	А
I <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; sine-wave pulse	-	220.5	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 50 mA	-	50	A/µs
I <sub>GM</sub>	peak gate current		-	5	А
$V_{GM}$	peak gate voltage		-	5	V
$P_{GM}$	peak gate power		-	20	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	1	W
T <sub>stg</sub>	storage temperature		-40	150	°C
T <sub>j</sub>	junction temperature		-	150	°C

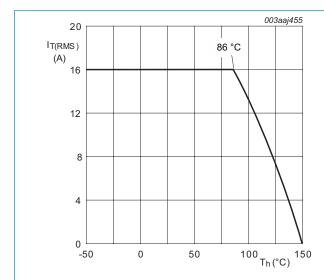
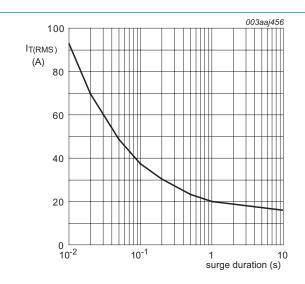
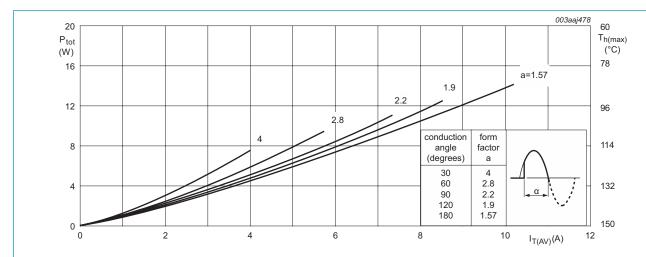


Fig. 1. RMS on-state current as a function of heatsink temperature; maximum values

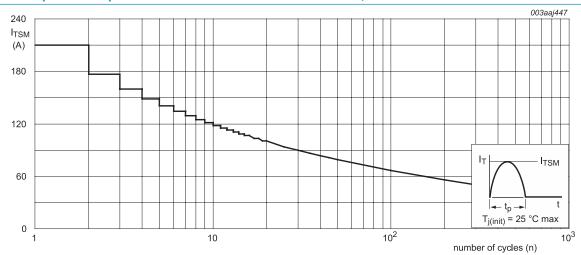


f = 50 Hz; T<sub>h</sub> = 86 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



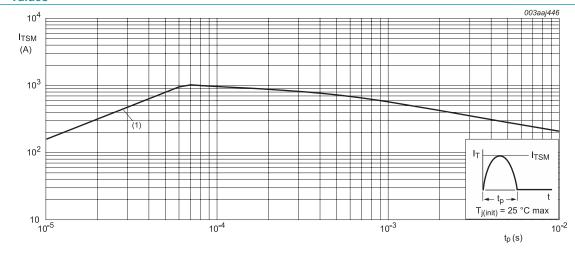
 $\alpha$  = conduction angle

 $a = form \ factor = I_{T(RMS)}/I_{T(AV)}$  Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



 $t_{D} \le 10 \text{ ms}$ 

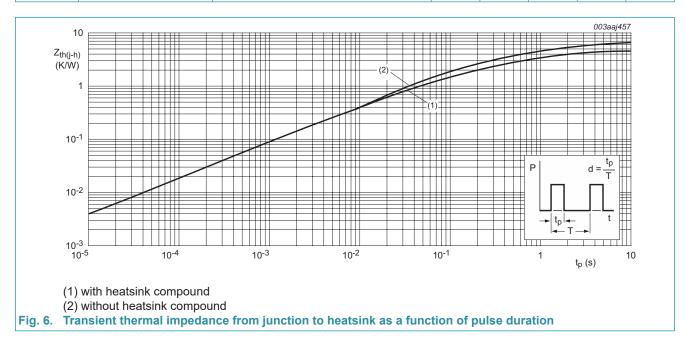
 $(1) dI_{T}/dt limit$ 

Non-repetitive peak on-state current as a function of pulse duration; maximum values

### 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-h)</sub> thermal resistance		with heatsink compound; Fig 6	-	-	4.5	K/W
from junction to heatsink	without heatsink compound; Fig 6	-	-	6.5	K/W	
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	-	55	-	K/W



## 10. Isolation characteristics

**Table 7. Isolation characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{\text{isol}(RMS)}$	RMS isolation voltage	50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
C <sub>isol</sub>	isolation capacitance	$f = 1 \text{ MHz}$ ; $T_h = 25 \text{ °C}$ ; from cathode to external heatsink	-	10	-	pF

### 11. Characteristics

**Table 8. Characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	racteristics			71		
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C; } Fig. 7$	-	4.5	25	mA
IL	latching current	$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; } T_j = 25 \text{ °C; } Fig. 8$	-	21	60	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	16	40	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 32 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.2	1.5	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A;} T_j = 25 \text{ °C; } Fig. 11$	-	0.7	1.3	V
		V <sub>D</sub> = 400 V; I <sub>T</sub> = 0.1 A;T <sub>j</sub> = 150 °C	0.2	0.4	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	0.2	1	mA
I <sub>R</sub>	reverse current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	0.2	1	mA
Dynamic	characteristics			1	·	
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	300	-	-	V/µs

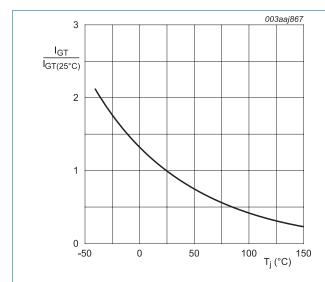


Fig. 7. Normalized gate trigger current as a function of junction temperature

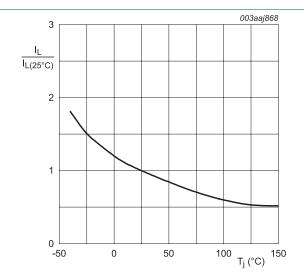


Fig. 8. Normalized latching current as a function of junction temperature

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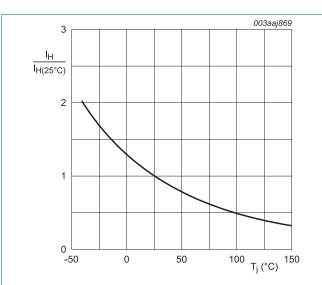
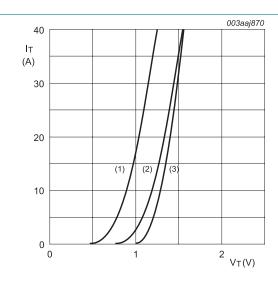


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o$  = 1.0336 V;  $R_s$  = 0.0141 Ω (1)  $T_j$  = 150 °C; typical values (2)  $T_j$  = 150 °C; maximum values (3)  $T_j$  = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

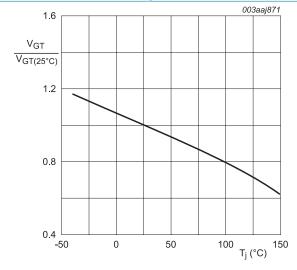
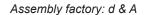
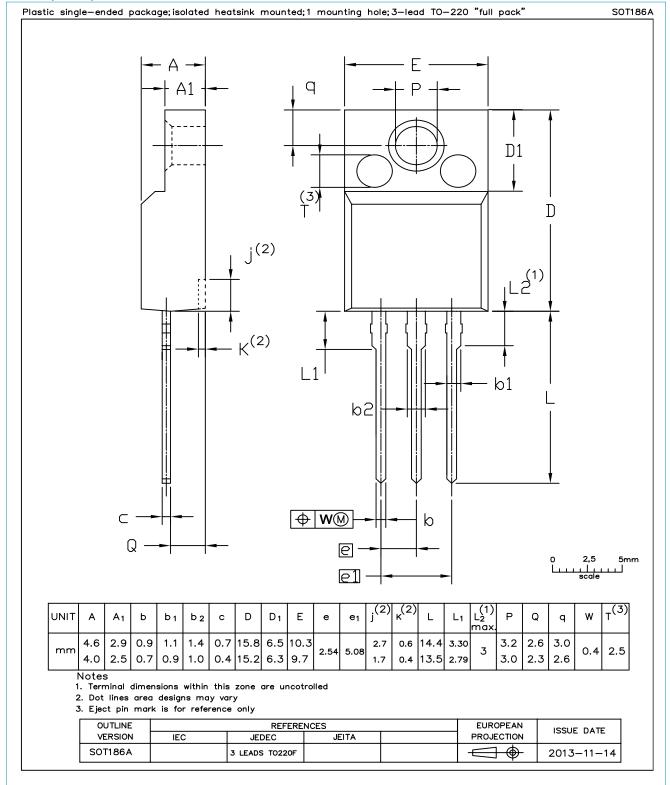


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

# 12. Package outline





## 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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	Features and benefits

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